

Notice of References Cited	Application/Control No. 10/619,369		Applicant(s)/Patent Under Reexamination TON ET AL.	
	Examiner Long P. Nguyen		Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0208183	10-2004	Balachandran et al.	370/395.21
*	B	US-6,771,966	08-2004	Chow, Peter El Kwan	455/446
*	C	US-6,940,824	09-2005	Shibutani, Akira	370/252
*	D	US-2005/0068902	03-2005	Rath, Kamlesh	370/256
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.